

<b>Search Notes</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10550619	TANAKA ET AL.
	Examiner	Art Unit
	Heyman, John	2871

### SEARCHED

Class	Subclass	Date	Examiner
349	15, text seaech	06/27/2007	JSH

### SEARCH NOTES

Search Notes	Date	Examiner
Consult Primary Examiner Andrew Schechter	06/27/2007	JSH

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner